



MOOV

MCSV : EVALUATE - Local Flatness Map

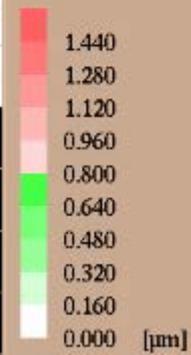
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19
1							0.051	0.051	0.035	0.048	0.065	0.056	0.044						
2					0.061	0.084	0.088	0.048	0.034	0.085	0.096	0.071	0.044	0.035	0.068				
3				0.051	0.045	0.086	0.094	0.119	0.087	0.097	0.094	0.085	0.053	0.045	0.078	0.078			
4			0.039	0.076	0.074	0.066	0.068	0.058	0.067	0.109	Max. 0.128	0.079	0.085	0.051	0.060	0.075	0.041		
5		0.054	0.089	0.106	0.064	0.110	0.053	0.088	0.076	0.078	0.085	0.100	0.088	0.040	0.024	0.050	0.059	0.063	
6		0.054	0.086	0.116	0.075	0.054	0.101	0.074	0.074	0.066	0.046	0.055	0.036	0.051	0.038	0.076	0.066	0.063	
7	0.030	0.040	0.063	0.075	0.064	0.065	0.090	0.054	0.050	0.039	0.030	0.044	0.050	0.053	0.054	0.046	0.085	0.040	0.020
8	0.038	0.054	0.056	0.088	0.074	0.041	0.048	0.043	0.035	0.043	0.043	0.044	0.050	0.058	0.064	0.054	0.034	0.026	0.026
9	0.034	0.048	0.074	0.054	0.088	0.053	0.061	0.068	0.046	0.031	0.030	0.024	0.036	0.053	0.056	0.041	0.030	0.066	0.074
10	0.051	0.064	0.071	0.098	0.053	0.061	0.053	0.054	0.054	0.033	0.026	0.015	0.030	0.051	0.055	0.064	0.048	0.056	0.066
11	0.045	0.068	0.055	0.045	0.049	0.060	0.038	0.048	0.046	0.078	0.053	0.065	0.048	0.053	0.064	0.053	0.080	0.046	0.046
12	0.068	0.061	0.033	0.036	0.051	0.055	0.036	0.046	0.036	0.065	0.068	0.063	0.060	0.060	0.068	0.058	0.040	0.065	0.068
13	0.059	0.058	0.051	0.046	0.061	0.051	0.026	0.043	0.044	0.046	0.061	0.034	0.056	0.076	0.068	0.094	0.056	0.054	0.065
14		0.035	0.051	0.084	0.045	0.050	0.035	0.039	0.049	0.045	0.070	0.075	0.055	0.045	0.026	0.052	0.046	0.044	
15		0.035	0.040	0.045	0.054	0.041	0.033	0.043	0.033	0.045	0.068	0.104	0.054	0.085	0.078	0.081	0.084	0.057	
16			0.038	0.029	0.054	0.045	0.029	0.029	0.031	0.088	0.061	0.063	0.046	0.059	0.075	0.079	0.085		
17				0.030	0.034	0.025	0.041	0.030	0.030	0.071	0.091	0.036	0.086	0.090	0.050	0.039			
18					Mn. 0.010	0.028	0.025	0.071	0.068	0.125	0.115	0.091	0.108	0.091	0.045				
19							0.028	0.058	0.065	0.066	0.103	0.066	0.108						

Local Flatness

Res.File : WF.WFLT
 Mac.ID :
 Date : 2021-02-16 10:26:44
 Comm. : 10000 * 10000 um pitch W

Disable Range : ----- [µm]

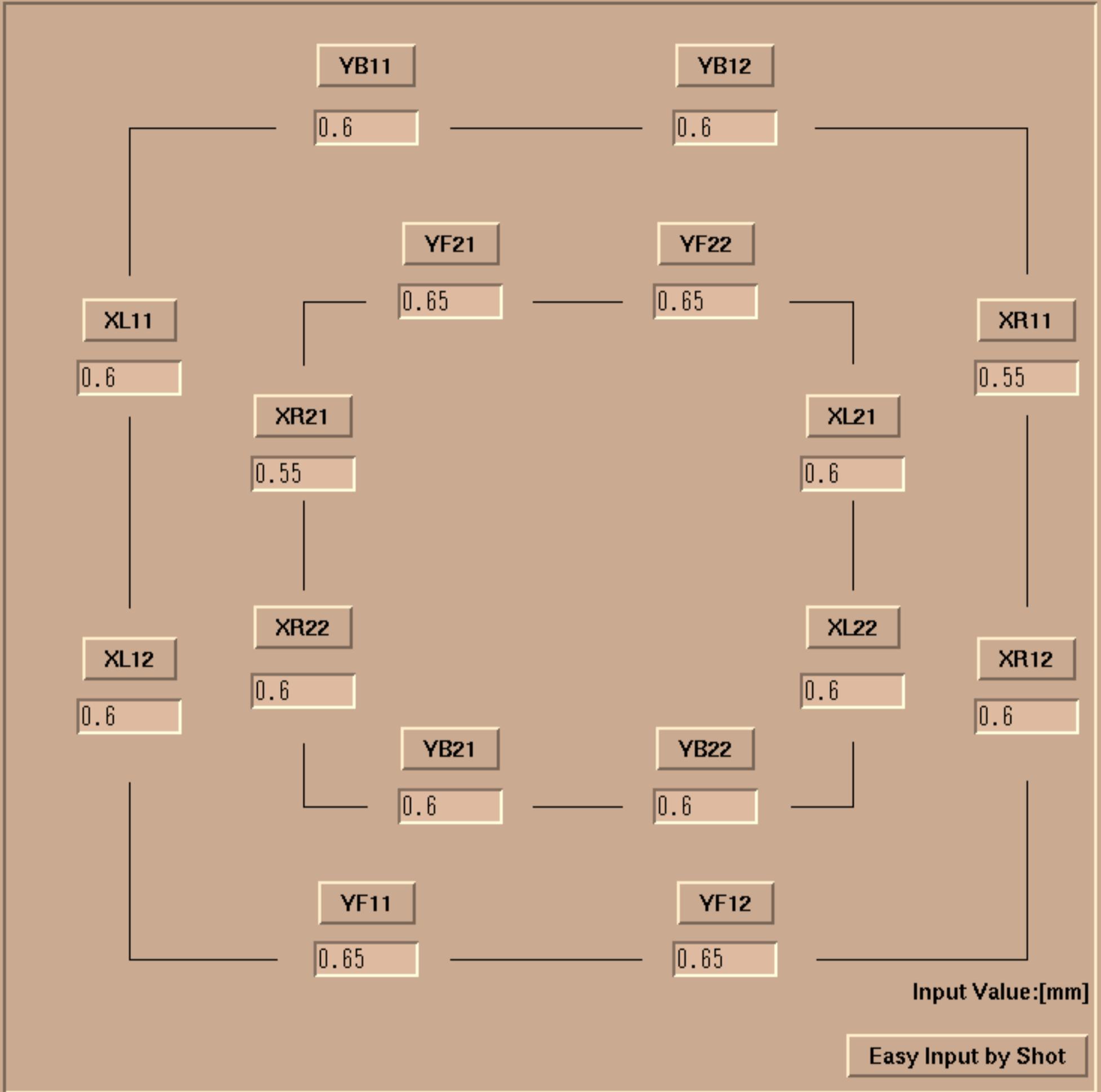
Wafer No. : 1
 Base Plane : Stage
 Max. : 0.171 [µm]
 Min. : -0.075 [µm]
 Max.-Min. : 0.246 [µm]
 L.F.S. Mode : 3AST
 L.F. Max. : 0.126 [µm]



- Disp. Mode
- Detail
 - Summary
 - 3D

F14
Exit

Calculation of Blind Parameters (Dynamic) For 2204HB_800



Set Option **Search W.Center** **Easy Input All** **Select**

Exit **Calc.** **Disp.**

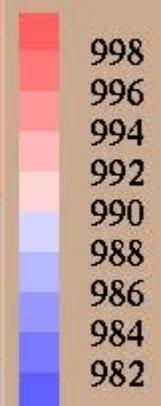
	1	2	3	4	5	6	7	8	9	10	11
1	Min. 975	982	984	982	981	984	980	979	979	978	981
2	977	985	986	984	982	985	982	981	981	981	985
3	982	991	992	989	988	990	988	987	988	987	993
4	987	995	995	993	992	995	993	991	992	994	997
5	989	997	999	996	995	998	995	993	994	996	999
6	987	996	998	998	996	999	996	993	994	995	1000
7	986	996	999	998	996	999	995	993	994	996	Max. 1000
8	983	992	996	994	993	996	992	990	990	993	996
9	979	990	991	990	989	991	987	986	986	988	991
10	979	988	989	989	988	988	986	984	984	987	988
11	981	991	994	993	993	992	988	985	986	987	988

Illumination Uniformity

Res.File : LAMP_CE.LAMP
 Mac.ID :
 Date : 2021-02-24 11:51:34
 Comm. : Lamp Uniformity Cond

Illumination ID :
 Center
 Maximum : 1000.00
 Minimum : 975.11
 Center (Integral)
 Maximum : 1003.17
 Minimum : 992.39
 Uniformity : 0.54 [%]
 Illumination
 Power : 1129.24 [mW/cm²]

Intra-field Repeat Count : 1
 Intra-field Repeat No. 1



Disp. Mode

- ◆ Detail
- ◇ Summary
- ◇ 3D

F14
Exit

Dose Uniformity (Scan)

File : 210224_25mm_LAMP_DYN.LAMP
 Machine ID :
 Date : 2021-02-24 11:55:05
 Comment : Lamp Uniformity Condition File (Scan)

Measurement Condition

Illumination ID : 5
 Intra-field Repeat Count : 1
 Map Layout
 Column : 21
 Row Front : -----
 Row Center : 1
 Row Back : -----
 Measurement Limits
 -X : -12500.00 [μm]
 +X : 12500.00 [μm]
 Front -Y : ----- [μm]
 +Y : ----- [μm]
 Center -Y : 0.00 [μm]
 +Y : 0.00 [μm]
 Back -Y : ----- [μm]
 +Y : ----- [μm]
 Sensor Position
 X : -102700.00 [μm]
 Y : -158500.00 [μm]
 Average Number : 1
 Dose : 20.00 [mJ/cm^2]

Measurement Result

Maximum : 20.047
 Minimum : 19.839
 $3\sigma/\text{mean}$: 0.007
 Uniformity : 0.521 [%]
 Illumination Power : 1130.400 [mW/cm^2]

Intra-field Repeat No. 1

1



Prev.

Next

F12
Retry

F14
Exit



S306D

Session Applications Options Help

Operator : NIKON

2021-02-15 17:32

Processing : 1/1
Reject : 0

◇ Exposure
◆ Shot Information

(6, 8): Y EGA Result = 0.598
 (6, 8): X EGA Result = -0.005
 (7, 7): Y EGA Result = 0.590
 (7, 7): X EGA Result = -0.012
 (8, 8): Y EGA Result = 0.592
 (8, 8): X EGA Result = -0.008

g-EGA result

Wafer Scaling	:	-0.484,	-0.291	[ppm]
Wafer Orthogonality	:	0.045		[μrad]
Wafer Rotation	:	39.819		[μrad]
Wafer Offset	:	-0.023,	0.590	[μm]
Shot Scaling	:	0.000,	0.000	[ppm]
Shot Orthogonality	:	0.000		[μrad]
Shot Rotation	:	0.000		[μrad]
Random Factor	:	0.014,	0.013	[μm]

Sensor Calibration

Reticle : Alignment Checked
 LSA : Calib. with Reticle
 FIA : Calib. with Reticle
 LIA : -----
 Stage : Calibrated

LC : Controlled

Focus Calib. : ----- [μm]
 Lens Mag. : ----- [μm]

Alignment Sensor

Search : FIA
 g-EGA : FIA
 t-EGA : -----
 D/D : -----



DECTerm

PAUSE(Quick)

PAUSE



DECTerm

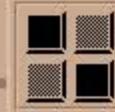
RESUME

STOP



MSM

HELP



UTLY CM





S306D()

Session Applications Options Help

Operator : NIKON

2021-02-15 17:43

Processing : 1/1
Reject : 0

◆ Exposure
◆ Shot Information

(6, 8): Y EGA Result = -0.082
 (6, 8): X EGA Result = -0.593
 (7, 7): Y EGA Result = -0.096
 (7, 7): X EGA Result = -0.573
 (8, 8): Y EGA Result = -0.082
 (8, 8): X EGA Result = -0.572

g-EGA result

Wafer Scaling	:	0.404,	-0.208	[ppm]
Wafer Orthogonality	:	-0.364		[μrad]
Wafer Rotation	:	103.925		[μrad]
Wafer Offset	:	-0.572,	-0.095	[μm]
Shot Scaling	:	0.000,	0.000	[ppm]
Shot Orthogonality	:	0.000		[μrad]
Shot Rotation	:	0.000		[μrad]
Random Factor	:	0.018,	0.027	[μm]

Calculator

File Edit Mode Help

-0.1595

digital™ 0.

MC	MR	M+	M-		
deg	x!	1/x	Rnd		
Inv	sin	cos	tan		
log	ln	√	y^x		
C	7	8	9	/	±
	4	5	6	*	%
CE	1	2	3	-	
	0	.	π	+	=

DECterm

PAUSE(Quick)

PAUSE

RESUME

STOP

HELP

MSM

UTLY CM

Measured Data

Date : 2021-03-09 17:18:09
 Comm. : % Stepping accuracy(3STEP)

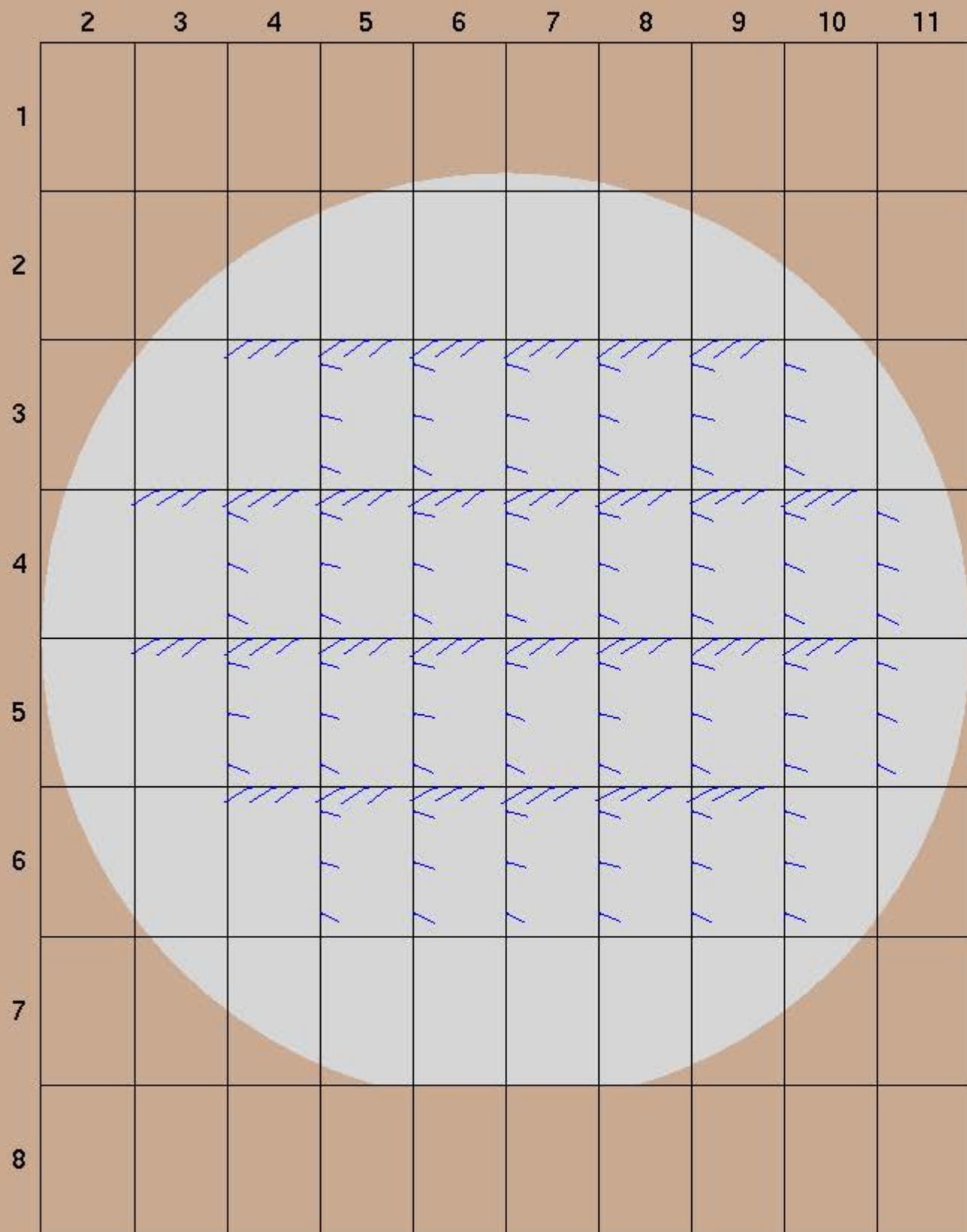
.231

Vector Scale [μm]



Each Wafer

	Xave	X3sig	Yave	Y3sig
1 SX1	0.098	0.014	-0.031	0.014
2 SX2	0.096	0.016	-0.029	0.015
3 SX3	0.093	0.018	-0.041	0.013
4 SY1	-0.121	0.015	-0.076	0.017
5 SY2	-0.112	0.014	-0.077	0.017
6 SY3	-0.098	0.013	-0.076	0.017
Total	-0.007	0.311	-0.055	0.066



F14
Exit

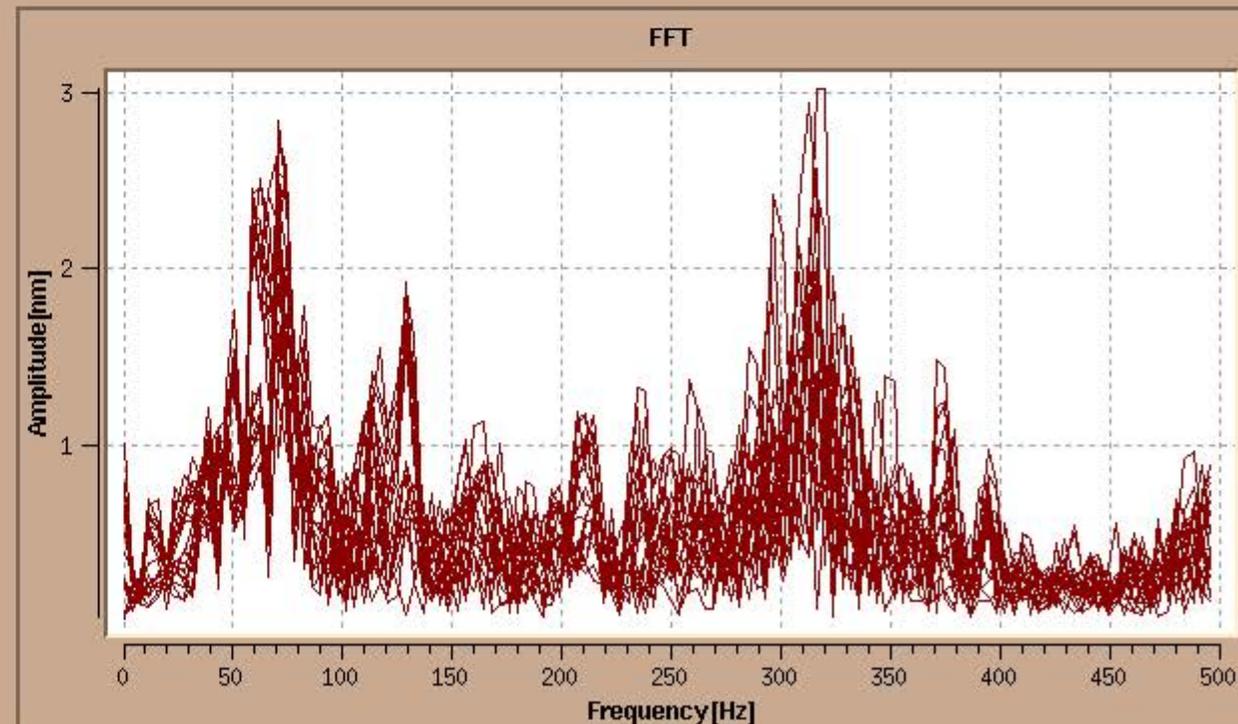
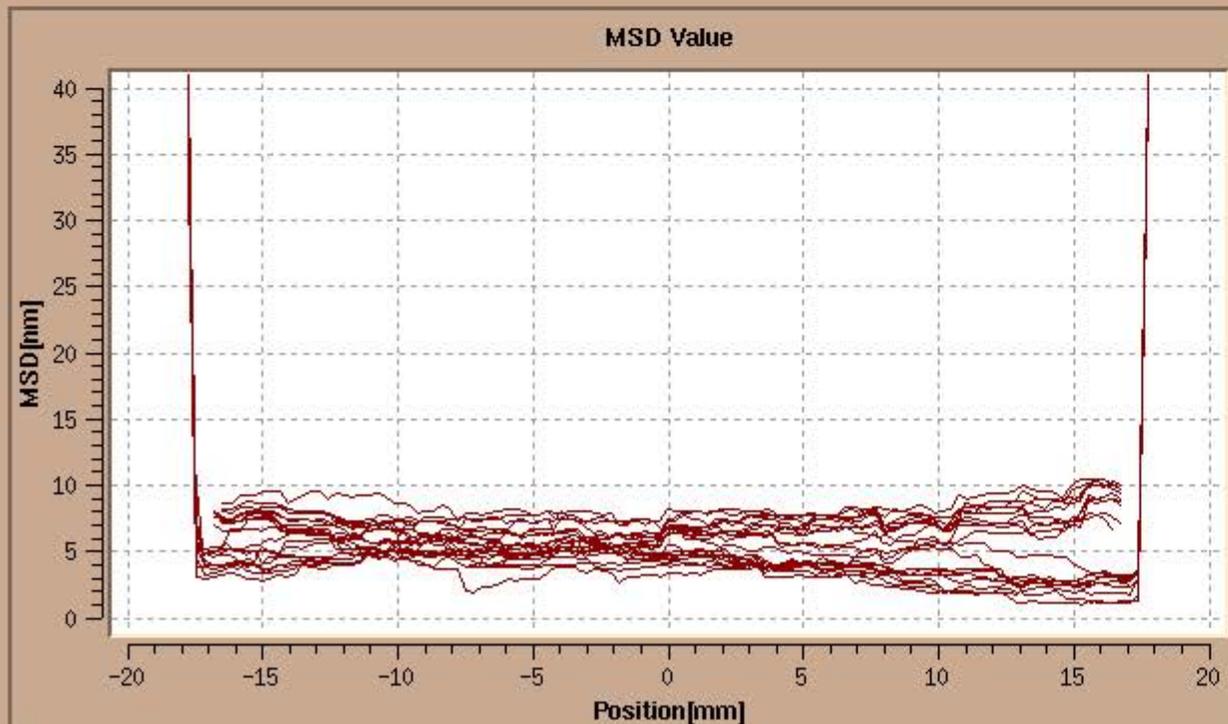
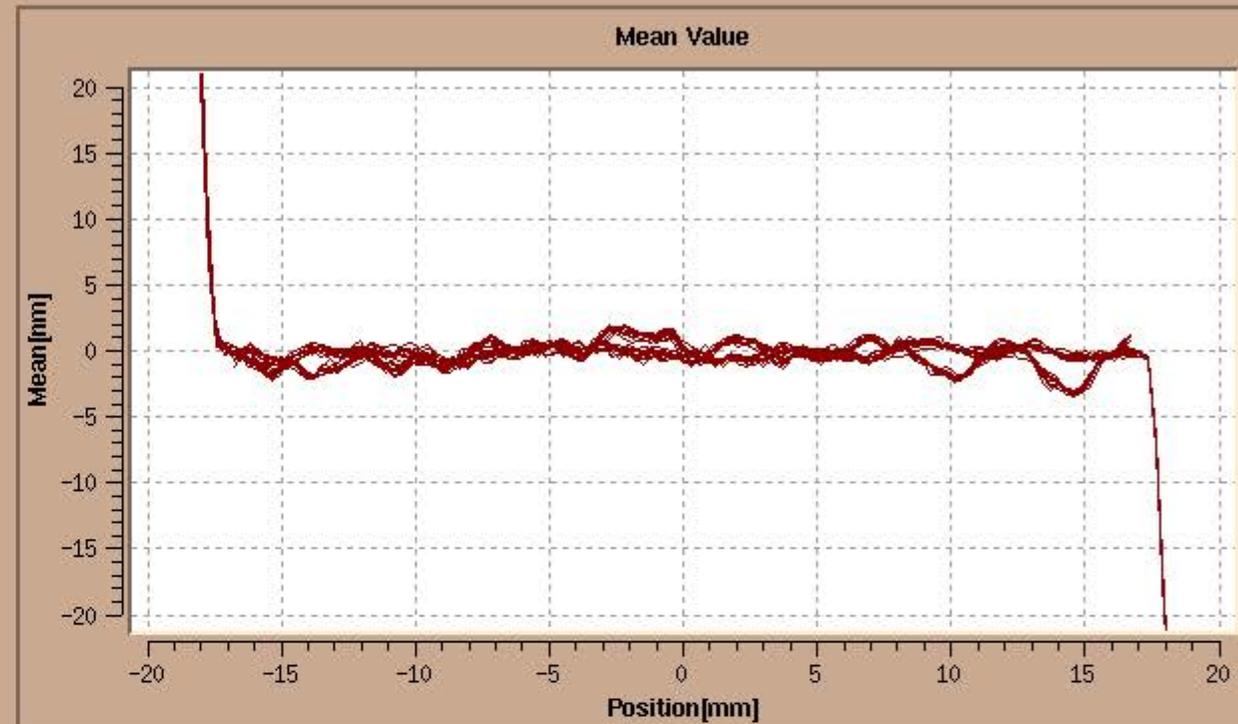
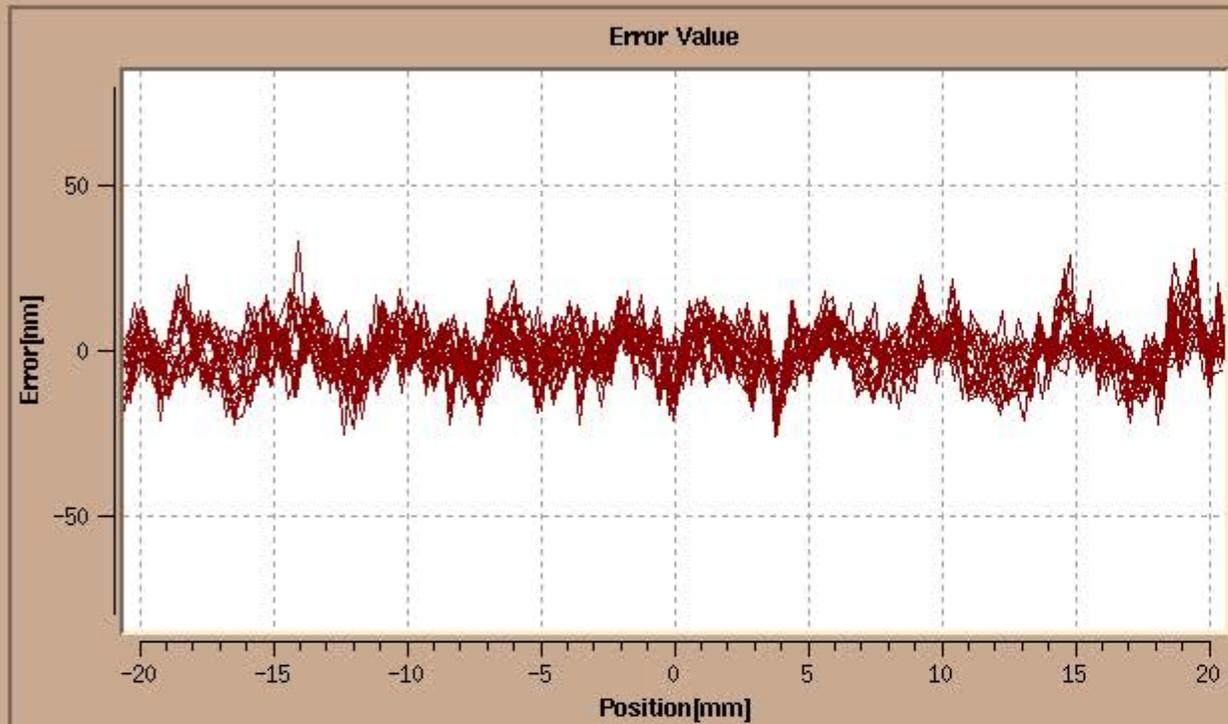
Error+Mean+MSD+FFT

Result File Name: T...

Date: 15-FEB-2021 15:22:54 Comment:

SPETU Mode: Normal Scan Speed[mm/sec]: 300.0 ILC Value: Valid Prefetch: Off

Axis: X Scan Direction: Both



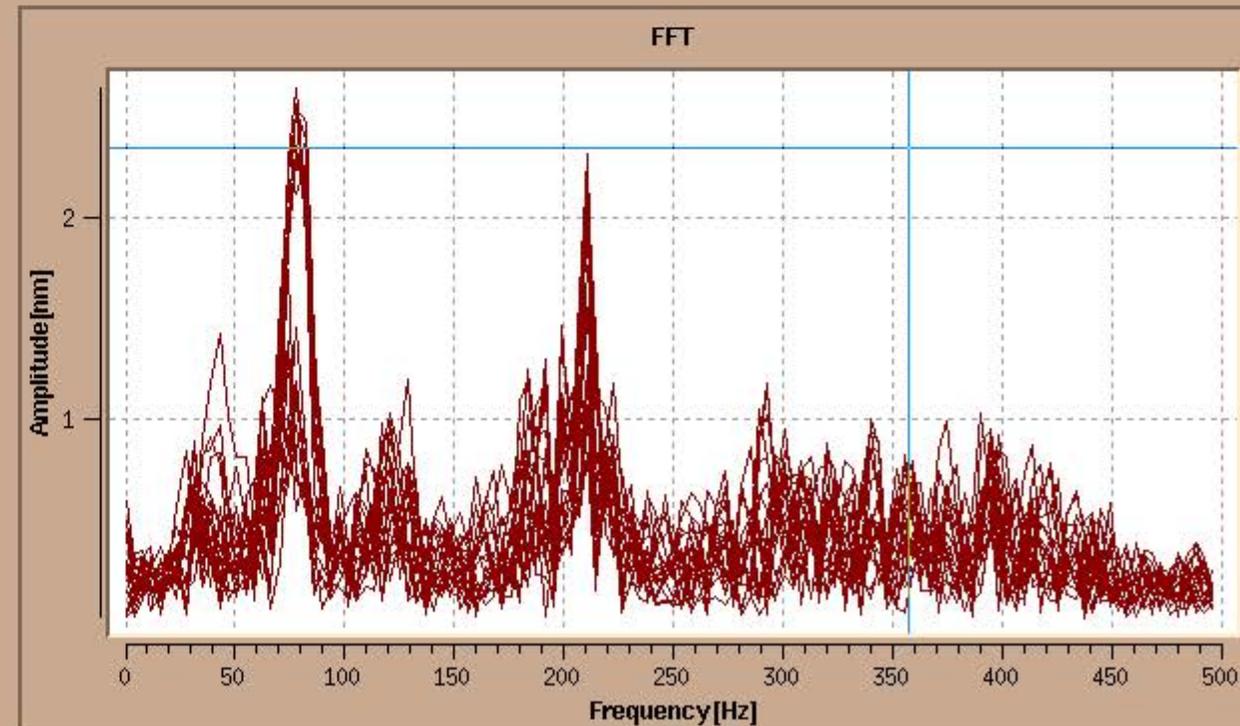
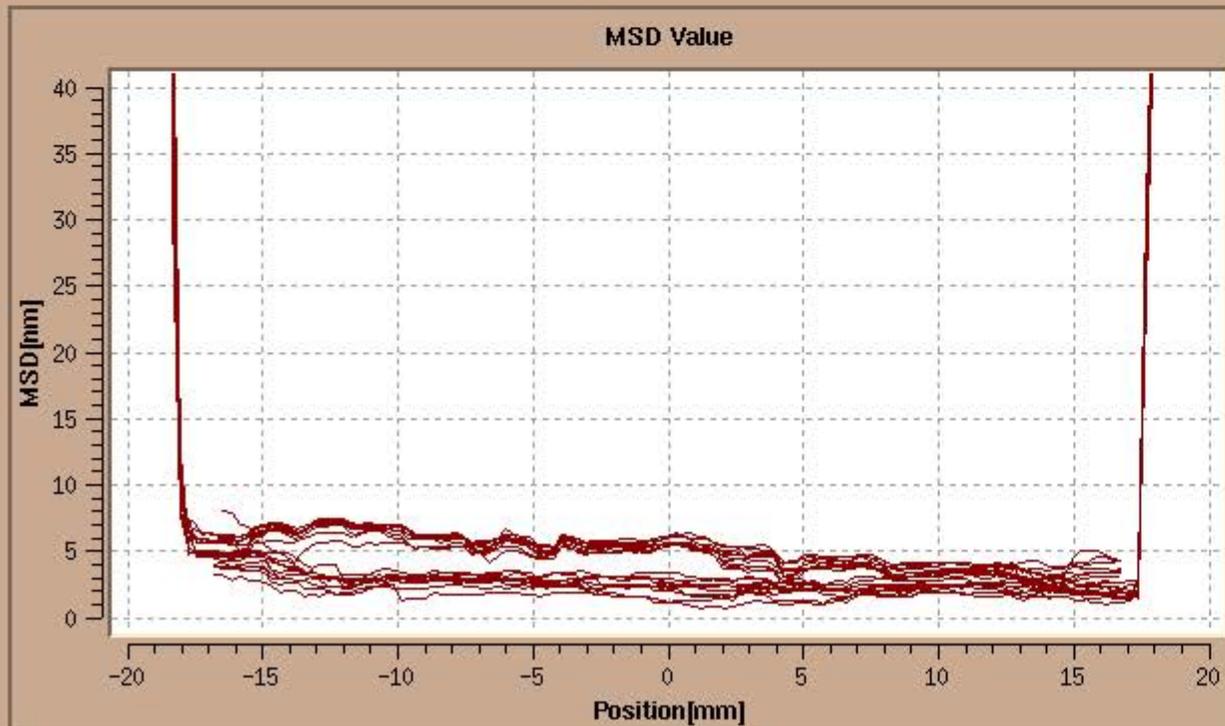
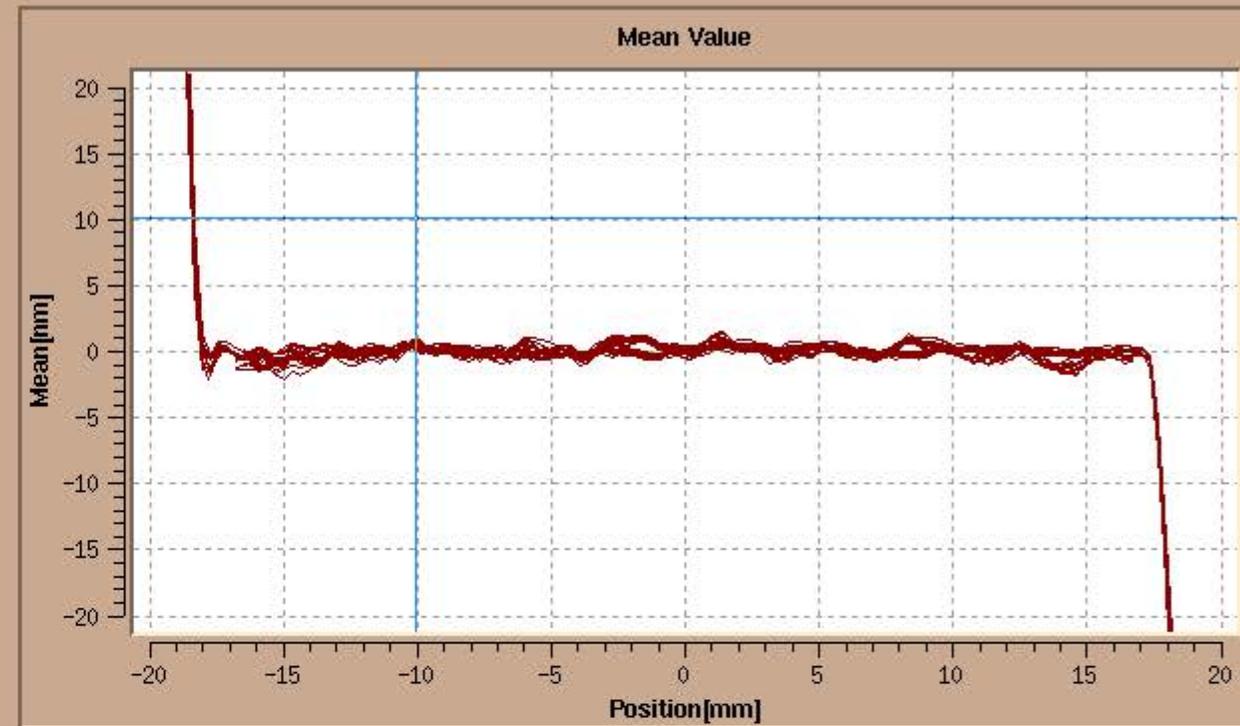
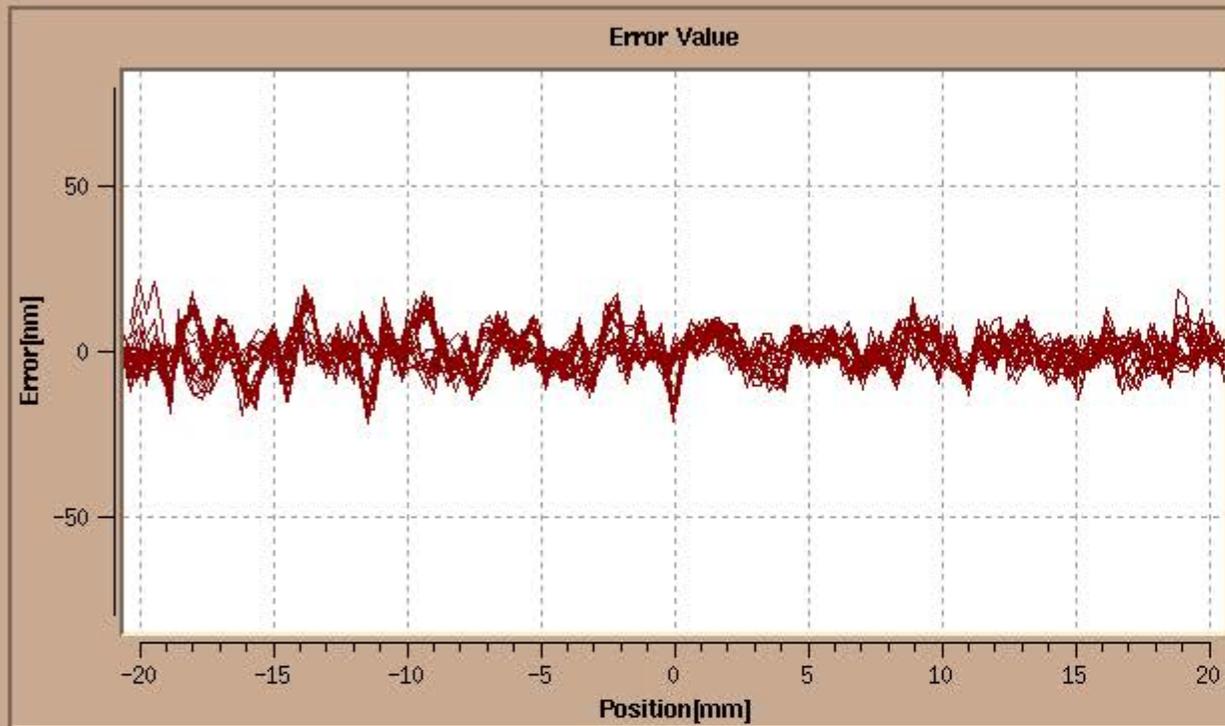
Error+Mean+MSD+FFT

Result File Name: 

Date: 15-FEB-2021 15:22:54 Comment:

SPETU Mode: Normal Scan Speed[mm/sec]: 300.0 ILC Value: Valid Prefetch: Off

Axis: YLR Scan Direction: Both



Wafer Loader Measurement Result

Measure Program

Date

Machine ID

Mode Normal

Wafer Count 1

Measure Count 30

	Y	THETA	Y-THETA	X	ROT	CenterX	CenterY	PRE-X	PRE-Y	PRE-ROT
	[um]	[um]	[um]	[um]	[urad]	[um]	[um]	[um]	[um]	[urad]
3Sgm(n-1)	2.128	2.646	2.848	3.594	44.846	3.236	1.941	23.221	51.162	240.700
Average	-1.308	-1.407	0.099	0.661	1.562	0.636	-1.359	-70.784	88.752	212.097
Max - Min	2.742	3.253	4.755	5.056	74.884	4.452	2.988	34.329	65.307	316.074

Rotation : 1.562 [urad]

Pre-align. X : 0.636 [um]

Pre-align. Y : -1.359 [um]

F7
Write

F14
Close

posure

Informatic

SE(Quick)

PAUSE

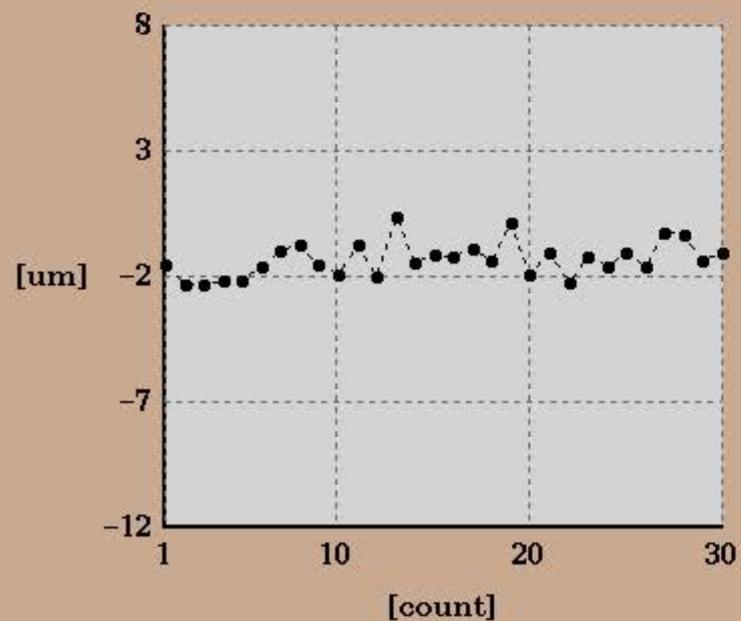
RESUME

STOP

ygraph

Graph

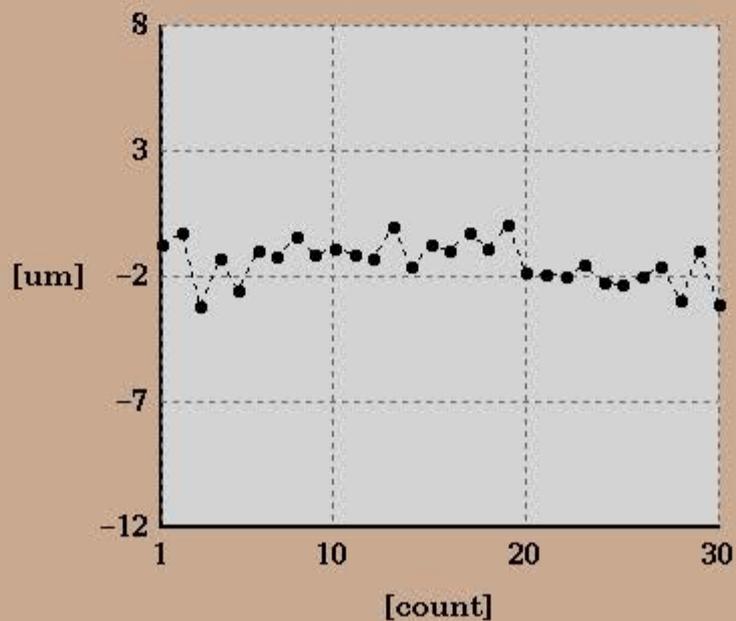
Y Data



tgraph

Graph

Theta Data



xgraph

Graph

X Data

